

Power MOSFET

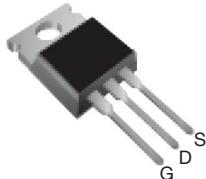
PRODUCT SUMMARY		
V _{DS} (V)	650	
R _{DS(on)} (Ω)	V _{GS} = 10 V	8.5
Q _g (Max.) (nC)	14	
Q _{gs} (nC)	2.7	
Q _{gd} (nC)	8.1	
Configuration	Single	

FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current



TO-220AB

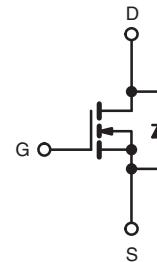


APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- Power Factor Correction

TYPICAL SMPS TOPOLOGIES

- Low Power Single Transistor Flyback



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)			
PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	650	V
Gate-Source Voltage	V _{GS}	± 30	
Continuous Drain Current	I _D	1.4 0.89	A
Pulsed Drain Current ^a	I _{DM}	5.6	
Linear Derating Factor		0.28	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	93	mJ
Repetitive Avalanche Current ^a	I _{AR}	1.4	A
Repetitive Avalanche Energy ^a	E _{AR}	3.6	mJ
Maximum Power Dissipation	P _D	36	W
Peak Diode Recovery dV/dt ^c	dV/dt	3.8	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature) ^d	for 10 s	300	

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Starting T_J = 25 °C, L = 95 mH, R_g = 25 Ω, I_{AS} = 1.4 A (see fig. 12).
- I_{SD} ≤ 1.4 A, dI/dt ≤ 180 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.
- 1.6 mm from case.

THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	110	$^{\circ}\text{C}/\text{W}$
Maximum Junction-to-Ambient (PCB Mount) ^a	R_{thJA}	-	50	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	3.5	

Note

- a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS ($T_J = 25^{\circ}\text{C}$, unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$		650	-	-	V
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2.0	-	4.0	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 650 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA
		$V_{DS} = 520 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 150^{\circ}\text{C}$		-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 0.84 \text{ A}^b$	-	8.5	-	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 0.84 \text{ A}$		0.88	-	-	S
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	229	-	pF
Output Capacitance	C_{oss}			-	32.6	-	
Reverse Transfer Capacitance	C_{rss}			-	2.4	-	
Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}$	$V_{DS} = 1.0 \text{ V}$, $f = 1.0 \text{ MHz}$	-	320	-	
			$V_{DS} = 480 \text{ V}$, $f = 1.0 \text{ MHz}$	-	11.5	-	
Effective Output Capacitance	$C_{oss eff.}$		$V_{DS} = 0 \text{ V to } 480 \text{ V}^c$	-	130	-	
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 1.4 \text{ A}$, $V_{DS} = 400 \text{ V}$, see fig. 6 and 13 ^b	-	-	14	nC
Gate-Source Charge	Q_{gs}			-	-	2.7	
Gate-Drain Charge	Q_{gd}			-	-	8.1	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 250 \text{ V}$, $I_D = 1.4 \text{ A}$, $R_g = 2.15 \Omega$, $R_D = 178 \Omega$, see fig. 10 ^b		-	9.8	-	ns
Rise Time	t_r			-	14	-	
Turn-Off Delay Time	$t_{d(off)}$			-	18	-	
Fall Time	t_f			-	20	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	 MOSFET symbol showing the integral reverse p-n junction diode		-	-	1.4	A
Pulsed Diode Forward Current ^a	I_{SM}			-	-	5.6	
Body Diode Voltage	V_{SD}	$T_J = 25^{\circ}\text{C}$, $I_S = 1.4 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.6	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^{\circ}\text{C}$, $I_F = 1.4 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	290	440	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	510	760	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.
c. $C_{oss eff.}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS} .

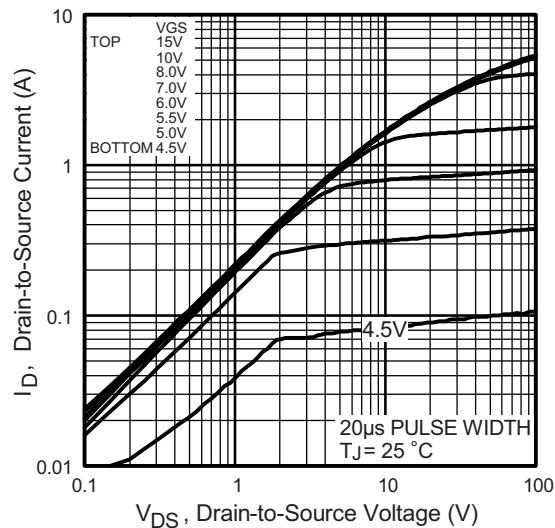
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Fig. 1 - Typical Output Characteristics

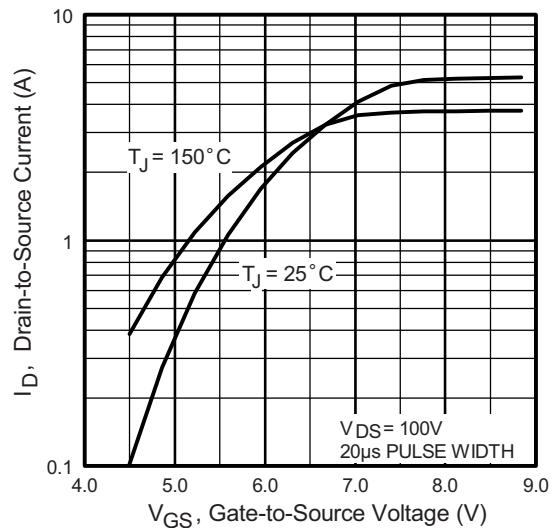


Fig. 3 - Typical Transfer Characteristics

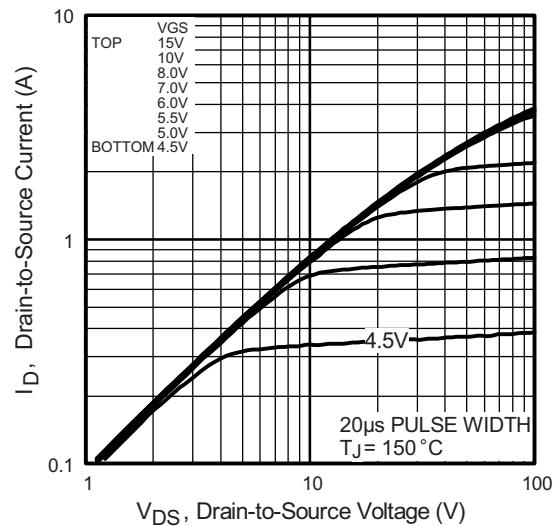


Fig. 2 - Typical Output Characteristics

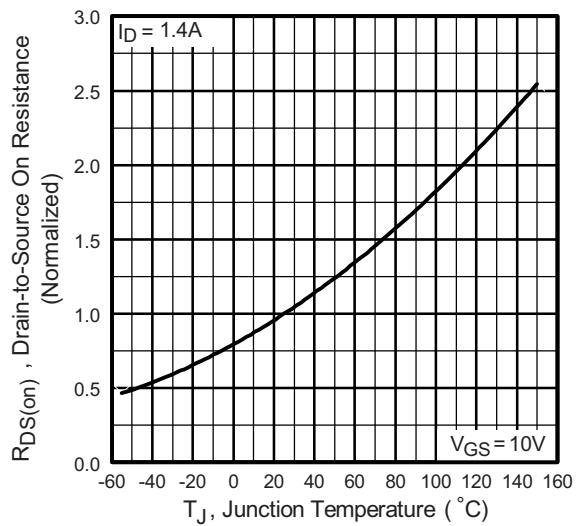
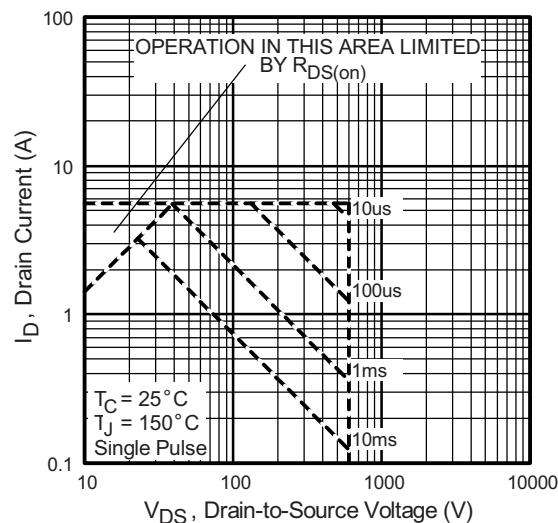
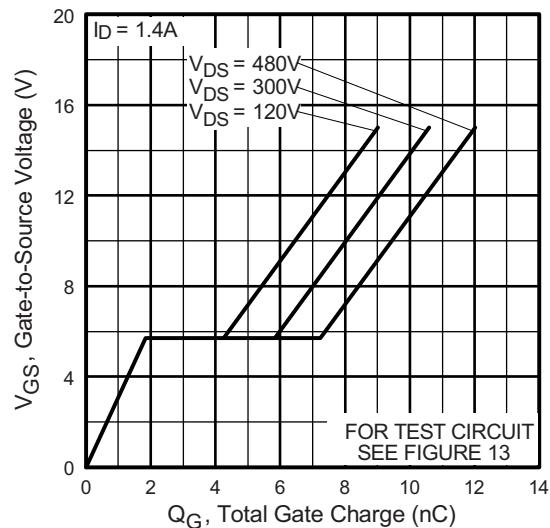
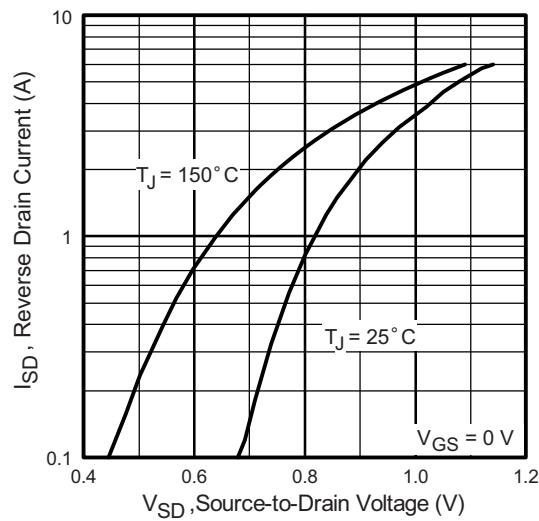
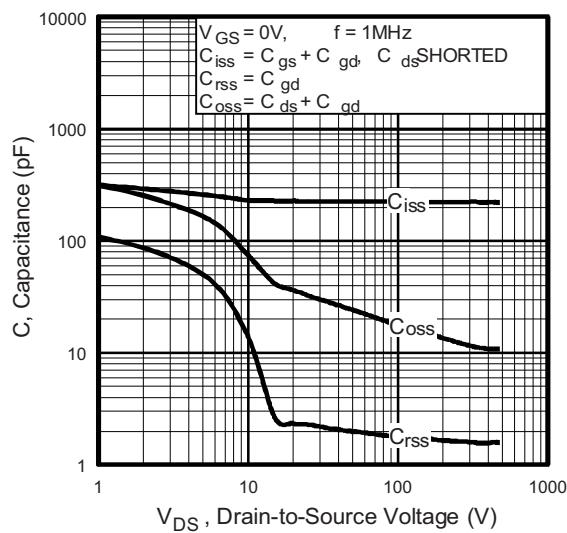


Fig. 4 - Normalized On-Resistance vs. Temperature



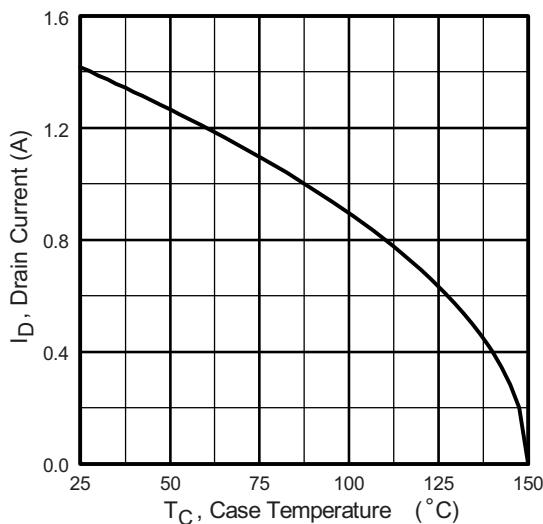


Fig. 9 - Maximum Drain Current vs. Case Temperature

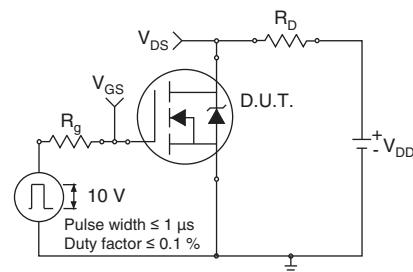


Fig. 10a - Switching Time Test Circuit

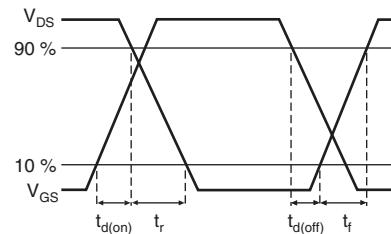


Fig. 10b - Switching Time Waveforms

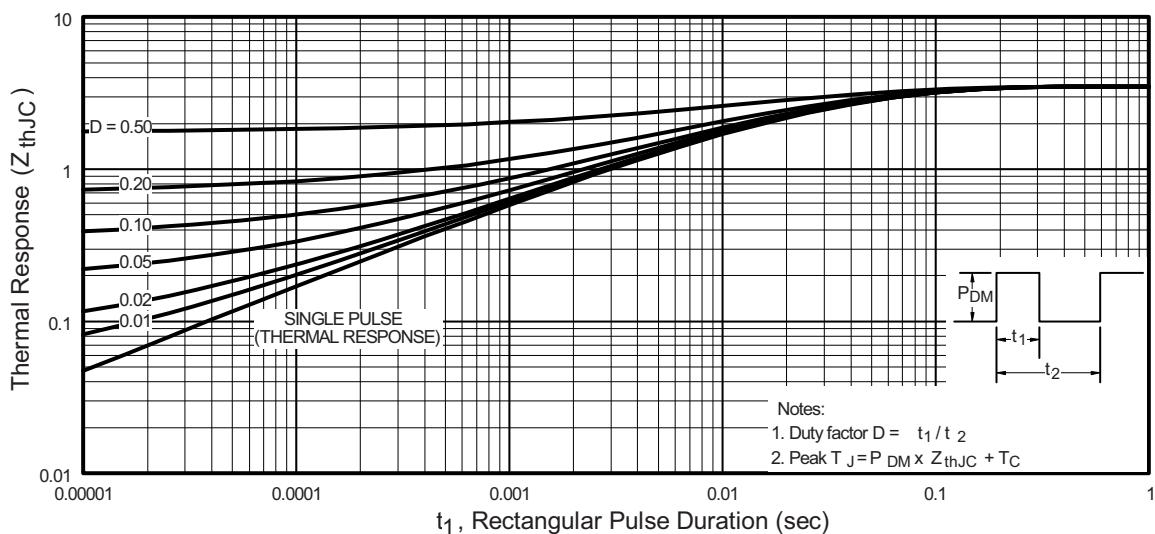


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

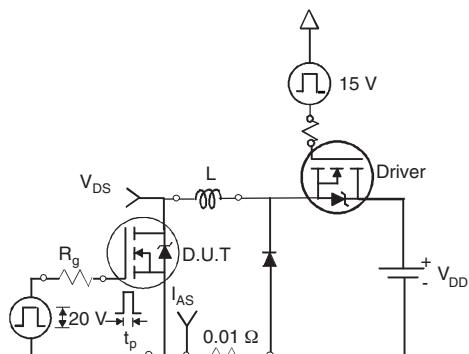


Fig. 12a - Unclamped Inductive Test Circuit

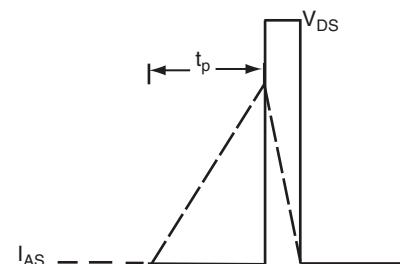


Fig. 12b - Unclamped Inductive Waveforms

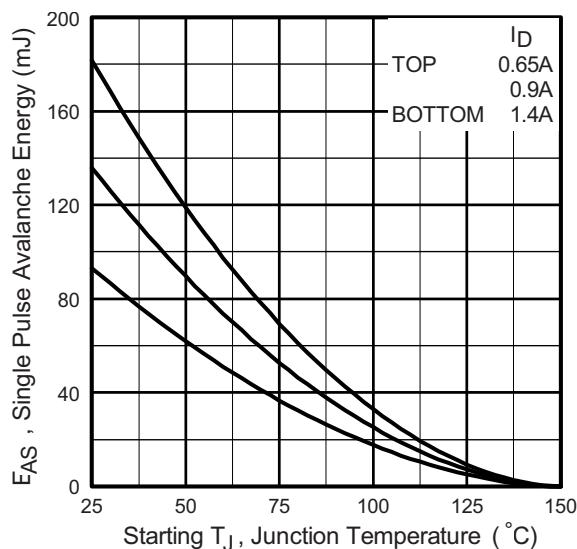


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

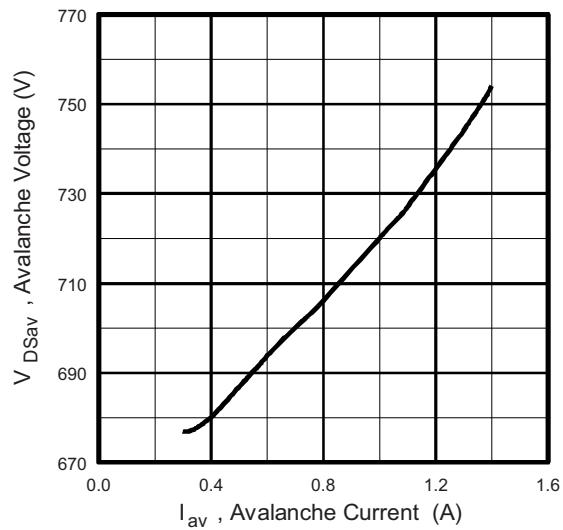


Fig. 12d - Basic Gate Charge Waveform

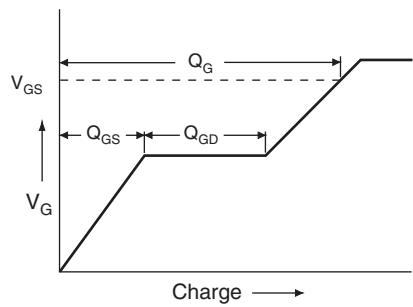


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

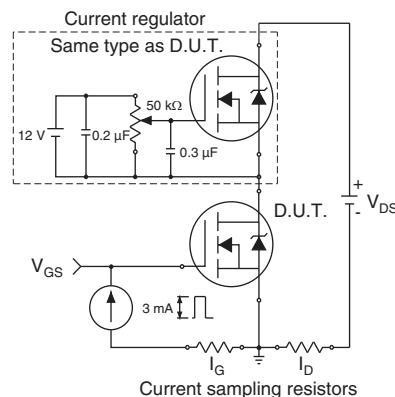
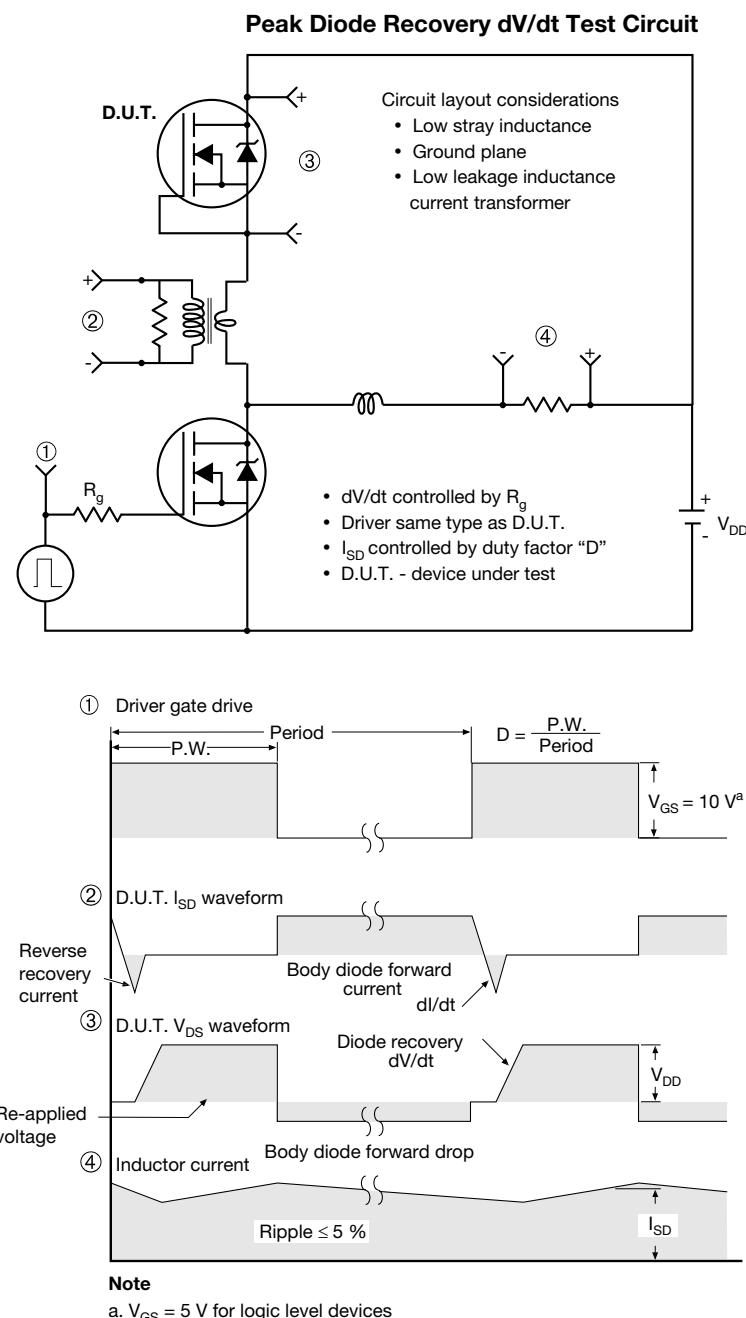
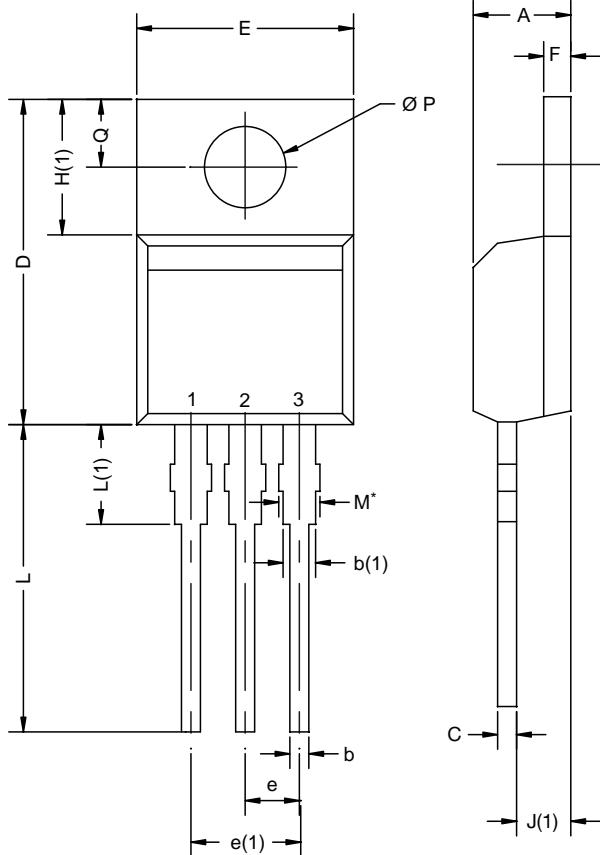


Fig. 13b - Gate Charge Test Circuit

**Fig. 14 - For N-Channel**

TO-220AB

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
c	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
e	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
Ø P	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471				

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion)
Heatsink hole for HVM

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